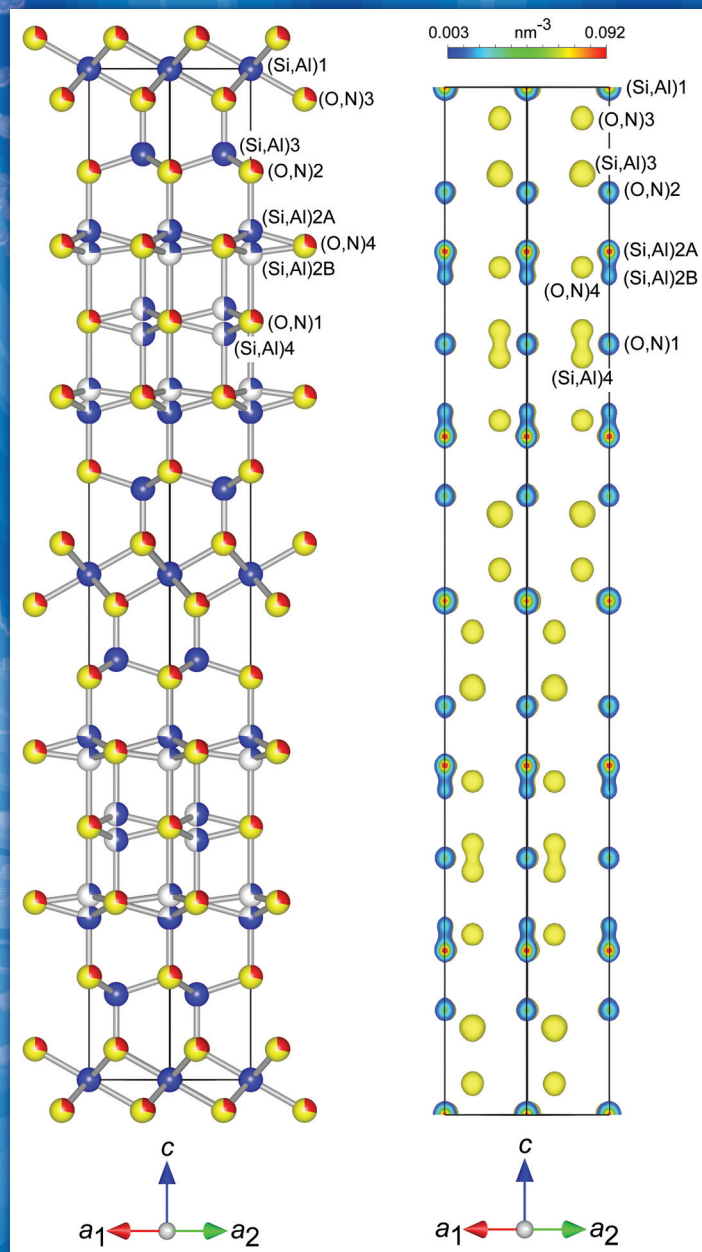


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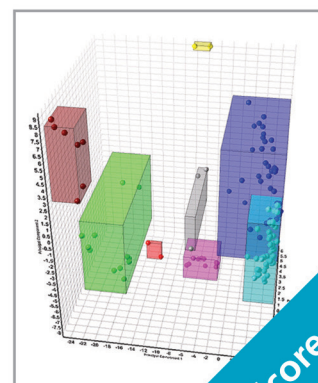
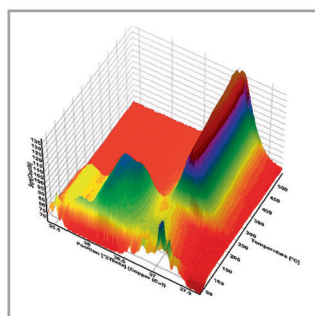
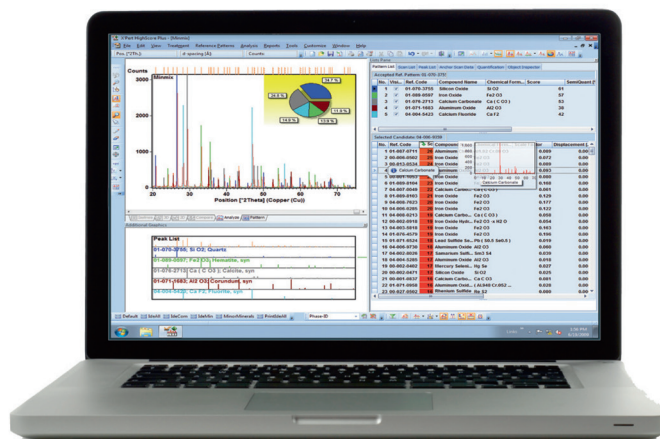
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T. Degen, M. Sadki, E. Bron, U. König, G. Nénert. The HighScore suite. Powder Diffraction (2014), doi:10.1017/S0885715614000840.

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Editor-in-Chief

Camden Hubbard
Applied Diffraction Services
110 Crestview Lane
Oak Ridge, Tennessee 37830, U.S.A.
camden.hubbard@me.com

Managing Editor

Nicole M. Ernst Boris
International Centre for Diffraction Data
12 Campus Boulevard
Newtown Square, Pennsylvania 19073-3273, U.S.A.
boris@icdd.com

Editor for New Diffraction Data

Soorya Kabekkodu
International Centre for Diffraction Data
12 Campus Boulevard
Newtown Square, Pennsylvania 19073-3273, U.S.A.
kabekkodu@icdd.com

Editors

Xiaolong Chen
Institute of Physics
Chinese Academy of Sciences
No. 8 Nanshanjie, Zhongguancun, Haidian District,
Beijing 100190,
China
xlchen@iphy.ac.cn

José Miguel Delgado
Universidad de Los Andes
Facultad de Ciencias
Departamento de Química
Lab. de Cristalografía
Mérida 5101
Venezuela
miguel@ula.ve

Norberto Masciocchi
Università dell'Insubria
Dipartimento di Scienza e Alta Tecnologia
via Valleggio 11
Como 22100
Italy
norberto.masciocchi@uninsubria.it

Editors for Crystallography Education

James Kaduk
Poly Crystallography Inc.
423 East Chicago Avenue
Naperville, Illinois 60540-5407, U.S.A.
Kaduk@polycrystallography.com

Brian H. Toby
Argonne National Laboratory
Advanced Photon Source
9700 S. Cass Ave., Bldg. 401/B4192,
Argonne, Illinois 60439-4856, U.S.A.
brian.toby@anl.gov

International Reports Editor

Winnie Wong-Ng
Materials Measurement Science Division
National Institute of Standards and Technology
100 Bureau Drive, Mail Stop 8520
Gaithersburg, MD 20899-8520, U.S.A.
winnie.wong-ng@nist.gov

Calendar of Meetings and Workshops Editor

Gang Wang
Institute of Physics
Chinese Academy of Sciences
No. 8 Nanshanjie, Zhongguancun, Haidian District,
Beijing 100190,
China
gangwang@iphy.ac.cn

On the Cover: Crystal structure of SiAl₅O₂N₅ and Three-dimensional electron-density distributions determined by MPF with the structural model (*Courtesy of Hiroki Banno, Takaaki Hanai, Toru Asaka, Koji Kimoto, Hiroimi Nakano, and Koichiro Fukuda*).

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Fundamentals of X-ray Powder Diffraction: 1–5 June 2015

For the novice with some XRD knowledge or for the experienced with an interest in the theory behind XRD, this clinic offers a strong base for increased lab performance.

The clinic covers instrumentation, specimen preparation, data acquisition and qualitative phase analysis. Hands-on use of personal computers for demonstration of the latest software; data mining with the PDF. The powder diffractometer: optical arrangement, factors affecting instrumental profile width, choice and function of divergence slit, detectors, X-ray optics, calibration and alignment.

***Advanced Methods in X-ray Powder Diffraction: 8–12 June 2015**

For the experienced XRD scientist, this clinic offers enhanced analysis skills through intense problem solving, as well as an introduction to the Rietveld Method. Computer-based methods of data collection and interpretation, both for qualitative and quantitative phase analysis is also emphasized.

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